



NOEL Technologies

## PLASMA ETCHING CAPABILITIES

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- Fluorine –Based Chemistries including CF<sub>4</sub> and SF<sub>6</sub> with O<sub>2</sub> and/or Argon Carrier Gas.
- Wafer sizes: 2" – 8"
- Blanket and patterned films including: PECVD Nitride, Polysilicon, a-Silicon, LPCVD Nitride, Polysilicon, a-Silicon, Thermally grown and Deposited oxides.
- Critical Dimension Features ranging from .2μm to 5mm Checkerboard patterns or Bond Pads.
- Photo resist Thickness Ranges: 6,000Å – 10.0μm
- Post Etch Photo resist Removal: EKC Solvent Strip, O<sub>2</sub> Plasma Ash or Piranha "Hot Sulfuric"
- Low Particle Post Resist Clean: SC1/SC2, Megasonic, LP Scrub
- X-Section SEMs Available upon request